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Patent Search

Invention Title	MACHINE LEARNING AND IMAGE MONITOR TO MONITOR THE DISEASE ON LEAF
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Abstract:

MACHINE LEARNING AND IMAGE MONITOR TO MONITOR THE DISEASE ON LEAF ABSTRACT The process of phenotyping plants is an essential part of describing plant track plant growth. Using image processing and machine learning approaches, this research presents an effective method for determining if a leaf is healthy, damage infected. The method is introduced in this publication. A number of diseases cause damage to the chlorophyll in leaves, which manifests as brown or black spots on t the leaf. Image preprocessing, image segmentation, feature extraction, and classification through the use of machine learning methods are all required to detect ther Level Co-occurrence Matrix, often known as GLCM, is utilized during the feature extraction process. Support Vector Machine, sometimes known as SVM, is an example classification algorithm that belongs to the field of machine learning. In comparison to the SVM method, the application of a Convolutional Neural Network (CNN) led recognition accuracy that was significantly enhanced.

Complete Specification

Description:FORM 2
THE PATENTS ACT,1970
(39 of 1970)
&
THE PATENT RULES, 2003
Complete Specification
(See section10 and rule13)
1. Title of the Invention: MACHINE LEARNING AND IMAGE MONITOR TO MONITOR THE DISEASE ON LEAF
2.Applicants

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